Se	earcn Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,194	BELKE ET AL.	
Examiner	Art Unit	
Cindy D. Khuu	2863	

SEARCHED			
Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
702	045	8/16/2005	СНК
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
US Patent East Databases: US-PGPUB, USPAT, USOCR, EPO, JPO,DERWENT, IBM_TDB	8/15/2005	СНК
PLUS	8/15/2005	снк
Michael Nghiem, AU2863: 702/45,47,50,100,189; 73/1.16,861	8/15/2005	снк
IEEE Explore	8/16/2005	СНК
702/45,47,50,100,189; 73/1.16,861: Text Only	8/16/2005	СНК